FAIRCHILD

SEMICONDUCTOR®

August 2013

FDMS86252L N-Channel Shielded Gate PowerTrench[®] MOSFET

FDMS86252L

N-Channel Shielded Gate PowerTrench[®] MOSFET 150 V, 12 A, 56 m Ω

Features

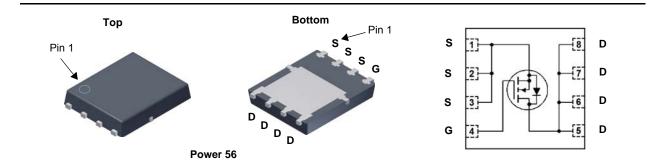
- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 56 m Ω at V_{GS} = 10 V, I_D = 4.4 A
- Max $r_{DS(on)}$ = 71 m Ω at V_{GS} = 6 V, I_D = 3.8 A
- Max r_{DS(on)} = 75 mΩ at V_{GS} = 4.5 V, I_D = 3.7 A
- Advanced package and silicon combination for low r_{DS(on)} and high efficiency
- Next generation enhanced body diode technology, engineered for soft recovery
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Applications

- OringFET / Load Switching
- Synchronous Rectification
- DC-DC Conversion



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V _{DS}	Drain to Source Voltage			150	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T _C = 25 °C		12	
I _D	-Continuous	T _A = 25 °C	(Note 1a)	4.4	Α
	-Pulsed		(Note 4)	30	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	73	mJ
P _D	Power Dissipation	T _C = 25 °C		50	w
	Power Dissipation $T_A = 25 \degree C$ (Note 1a)		(Note 1a)	2.5	V
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	2.5	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note 1a) 50	C/W

Package Marking and Ordering Information

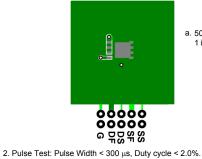
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86252L	FDMS86252L	Power 56	13 "	12 mm	3000 units

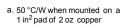
Parameter	Test Conditions	Min	Тур	Max	Units	
octeristics						
Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	150		1	V	
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		104		mV/°C	
Zero Gate Voltage Drain Current	V _{DS} = 120 V, V _{GS} = 0 V			1	μA	
Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA	
cteristics						
Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$	1	1.5	3	V	
Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		-6		mV/°C	
	V _{GS} = 10 V, I _D = 4.4 A		46	56		
Static Drain to Source On Resistance	V _{GS} = 6 V, I _D = 3.8 A		48	71	mΩ	
	V _{GS} = 4.5 V, I _D = 3.7 A		52	75		
	V _{GS} = 10 V, I _D = 4.4 A, T _J = 125 °C		90	110		
Forward Transconductance	V _{DS} = 5 V, I _D = 4.4 A		21		S	
Characteristics			952	1335	pF	
			74	105	pF	
· · ·	- f = 1 MHz		3	5	pF	
Gate Resistance		0.1	0.6	1.8	Ω	
g Characteristics					1	
,					ns	
					ns	
	VGS - 10 V, NGEN - 0 32			÷ .	ns	
					ns	
0					nC	
Gate to Source Charge	$V_{GS} = 0 \ V \ to \ 4.5 \ V \ DD = 75 \ V,$ $I_D = 4.4 \ A$		7.6 2.1	TT	nC nC	
			1 2 1	1	i nu	
	Intervision Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Intervision Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	InterfisticsDrain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 V$ Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A, referenced to 25 °C$ Zero Gate Voltage Drain Current $V_{DS} = 120 V, V_{GS} = 0 V$ Gate to Source Leakage Current $V_{GS} = \pm 20 V, V_{DS} = 0 V$ CeteristicsGate to Source Threshold VoltageTemperature Coefficient $I_D = 250 \mu A, referenced to 25 °C$ Static Drain to Source On Resistance $V_{GS} = 10 V, I_D = 4.4 A$ $V_{GS} = 6 V, I_D = 3.8 A$ $V_{GS} = 10 V, I_D = 4.4 A,$ $T_J = 125 °C$ Forward Transconductance $V_{DS} = 5 V, I_D = 4.4 A,$ CharacteristicsInput CapacitanceOutput CapacitanceGate Resistance g CharacteristicsTurn-On Delay TimeRise Time $V_{CS} = 10 V, R_{GEN} = 6 \Omega$ Fall TimeTotal Gate Charge $V_{GS} = 0 V to 10 V$	IncteristicsDrain to Source Breakdown Voltage $I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$ 150Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu A, \ referenced to 25 \ ^{\circ}C$ 2Zero Gate Voltage Drain Current $V_{DS} = 120 \ V, \ V_{GS} = 0 \ V$ 3Gate to Source Leakage Current $V_{DS} = 120 \ V, \ V_{DS} = 0 \ V$ 4CteristicsGate to Source Threshold Voltage $V_{GS} = 420 \ V, \ V_{DS} = 0 \ V$ Gate to Source Threshold Voltage $I_D = 250 \ \mu A$ 1Gate to Source Threshold Voltage $I_D = 250 \ \mu A$, referenced to $25 \ ^{\circ}C$ 4Gate to Source Threshold Voltage $I_D = 250 \ \mu A$, referenced to $25 \ ^{\circ}C$ 4Static Drain to Source On Resistance $V_{GS} = 10 \ V, \ I_D = 4.4 \ A$ 4 $V_{GS} = 10 \ V, \ I_D = 4.4 \ A$ $V_{GS} = 5 \ V, \ I_D = 4.4 \ A$ 4CharacteristicsInput Capacitance $V_{DS} = 75 \ V, \ V_{GS} = 0 \ V, \ f = 1 \ MHz$ 6Qutput Capacitance $0.11 \ M_{CS} = 10 \ V, \ R_{CS} = 0 \ V, \ f = 1 \ MHz$ 0.11 Characteristics Turn-On Delay Time $V_{CS} = 10 \ V, \ R_{GS} = 10 \ V, \ R_{S} = 10 \ V, \ R_{GS} = $	InteresticsDrain to Source Breakdown Voltage $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$ 150Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ C104Zero Gate Voltage Drain Current $V_{DS} = 120 \ V, V_{GS} = 0 \ V$ 10Gate to Source Leakage Current $V_{GS} = 120 \ V, V_{DS} = 0 \ V$ 10Gate to Source Threshold Voltage Temperature Coefficient $V_{GS} = 420 \ V, V_{DS} = 0 \ V$ 1Gate to Source Threshold Voltage Temperature Coefficient $V_{GS} = 10 \ V, I_D = 250 \ \mu$ A11.5Gate to Source Threshold Voltage Temperature Coefficient $V_{GS} = 10 \ V, I_D = 4.4 \ A$ 46 $V_{GS} = 4.5 \ V, I_D = 3.7 \ A$ 52 $V_{GS} = 10 \ V, I_D = 4.4 \ A$ 48 $V_{GS} = 10 \ V, I_D = 4.4 \ A$ 21CharacteristicsInput Capacitance Output Capacitance $V_{DS} = 75 \ V, V_{GS} = 0 \ V, f = 1 \ MHz$ 952Output Capacitance Output Capacitance0.1 0.6 g Characteristics 110 \ 0.61.4 \ 0.4 \		

V	Source-Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.9 A (Note 2)	0.7	1.2	V
V_{SD}	Source-Drain Diode Torward Voltage	$V_{GS} = 0 V, I_S = 4.4 A$ (Note 2)	0.8	1.3	v
t _{rr}	Reverse Recovery Time	I _E = 4.4 A, di/dt = 100 A/μs	53	85	ns
Q _{rr}	Reverse Recovery Charge	I _F = 4.4 A, di/dt = 100 A/μs 51 8.		82	nC

Notes:

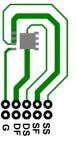
1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.





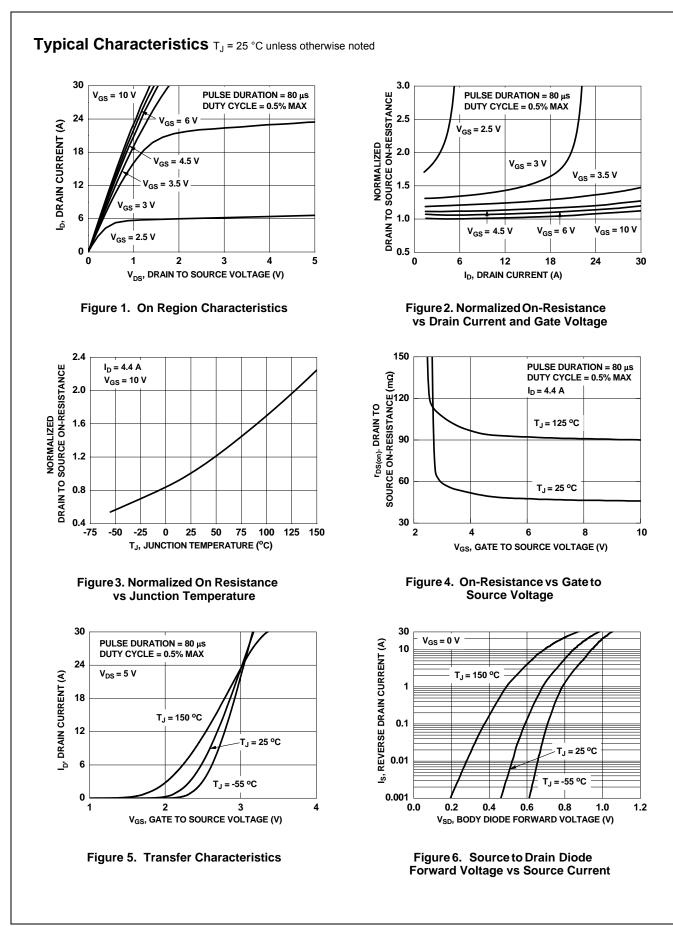
3. E_{AS} of 73 mJ is based on Starting T_J = 25 °C, L = 3 mH, I_{AS} = 7 A, V_{DD} = 150 V, V_{GS} = 10 V. 100% tested at L =0.1 mH, I_{AS} = 24 A.

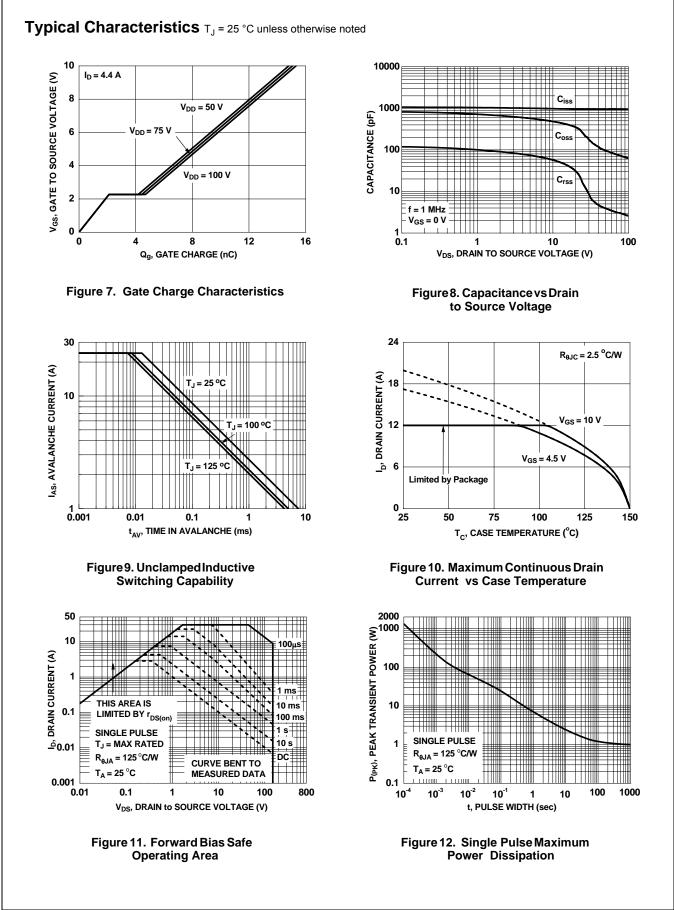
4. Pulsed Id limited by junction temperature, td<=100 μ S, please refer to SOA curve for more details.

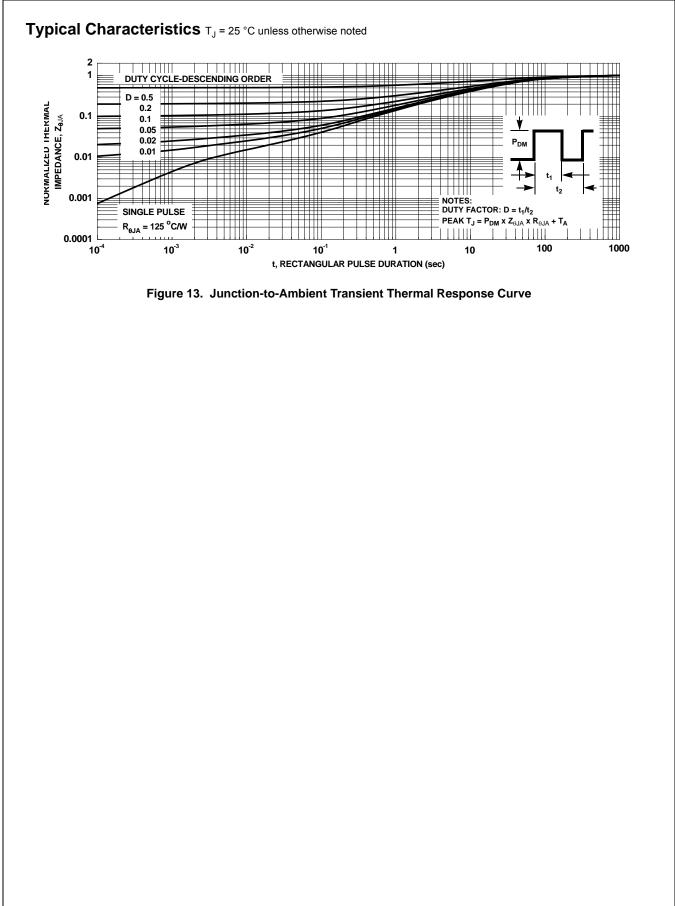


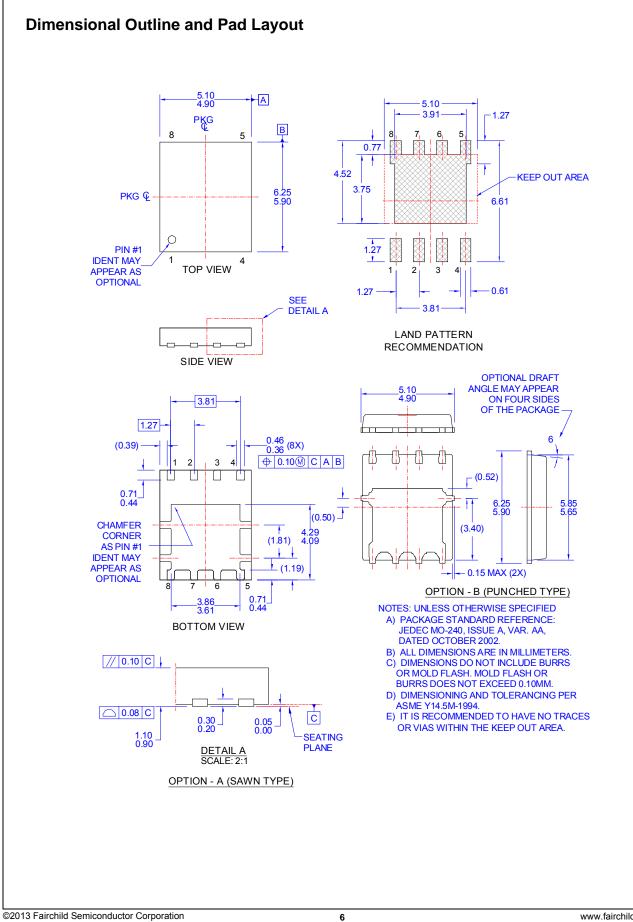
b. 125 °C/W when mounted on a minimum pad of 2 oz copper.











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